

MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DS}	Drain to Source Voltage	40	V
V_{GS}	Gate to Source Voltage	± 20	V
I_D	Drain Current Continuous ($T_C < 160^\circ\text{C}$, $V_{GS} = 10\text{V}$)	80	A
	Continuous ($T_{amb} = 25^\circ\text{C}$, $V_{GS} = 10\text{V}$, with $R_{\theta JA} = 43^\circ\text{C/W}$)	28	
	Pulsed	See Figure 4	
E_{AS}	Single Pulse Avalanche Energy (Note 1)	947	mJ
P_D	Power dissipation	300	W
	Derate above 25°C	2	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature	-55 to 175	$^\circ\text{C}$

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case	0.5	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (Note 2)	62	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient, 1in ² copper pad area	43	$^\circ\text{C/W}$

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB8441	FDB8441-F085	TO-263AB	330mm	24mm	800 units

Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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Off Characteristics

$B_{V_{DS}}$	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 32\text{V}$ $V_{GS} = 0\text{V}$ $T_J = 150^\circ\text{C}$	-	-	1	μA
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{V}$	-	-	± 100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	2	2.8	4	V
$r_{DS(on)}$	Drain to Source On Resistance	$I_D = 80\text{A}$, $V_{GS} = 10\text{V}$	-	1.9	2.5	m Ω
		$I_D = 80\text{A}$, $V_{GS} = 10\text{V}$, $T_J = 175^\circ\text{C}$	-	3.3	4.3	

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$	-	15000	-	pF
C_{oss}	Output Capacitance		-	1250	-	pF
C_{rss}	Reverse Transfer Capacitance		-	685	-	pF
R_G	Gate Resistance	$V_{GS} = 0.5\text{V}$, $f = 1\text{MHz}$	-	1.1	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0$ to 10V	-	215	280	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0$ to 2V	-	29	38	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DD} = 20\text{V}$ $I_D = 35\text{A}$ $I_g = 1\text{mA}$	-	60	-	nC
Q_{gs2}	Gate Charge Threshold to Plateau		-	32	-	nC
Q_{gd}	Gate to Drain "Miller" Charge		-	49	-	nC
			-			

Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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Switching Characteristics

t_{on}	Turn-On Time	$V_{\text{DD}} = 20\text{V}$, $I_{\text{D}} = 35\text{A}$ $V_{\text{GS}} = 10\text{V}$, $R_{\text{GS}} = 1.5\Omega$	-	-	77	ns
$t_{\text{d(on)}}$	Turn-On Delay Time		-	23	-	ns
t_{r}	Turn-On Rise Time		-	24	-	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		-	75	-	ns
t_{f}	Turn-Off Fall Time		-	17.9	-	ns
t_{off}	Turn-Off Time		-	-	147	ns

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Voltage	$I_{\text{SD}} = 35\text{A}$	-	0.8	1.25	V
		$I_{\text{SD}} = 15\text{A}$	-	0.8	1.0	V
t_{rr}	Reverse Recovery Time	$I_{\text{F}} = 35\text{A}$, $di/dt = 100\text{A}/\mu\text{s}$	-	52	68	ns
Q_{rr}	Reverse Recovery Charge	$I_{\text{F}} = 35\text{A}$, $di/dt = 100\text{A}/\mu\text{s}$	-	76	99	nC

Notes:1: Starting $T_J = 25^\circ\text{C}$, $L = 0.46\text{mH}$, $I_{\text{AS}} = 64\text{A}$.2: Pulse width = 100 μs .

Typical Characteristics

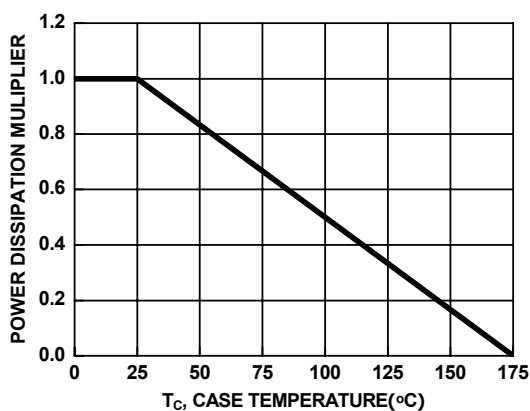


Figure 1. Normalized Power Dissipation vs Case Temperature

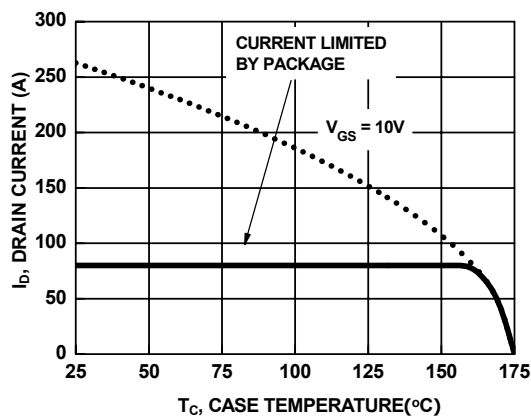


Figure 2. Maximum Continuous Drain Current vs Case Temperature

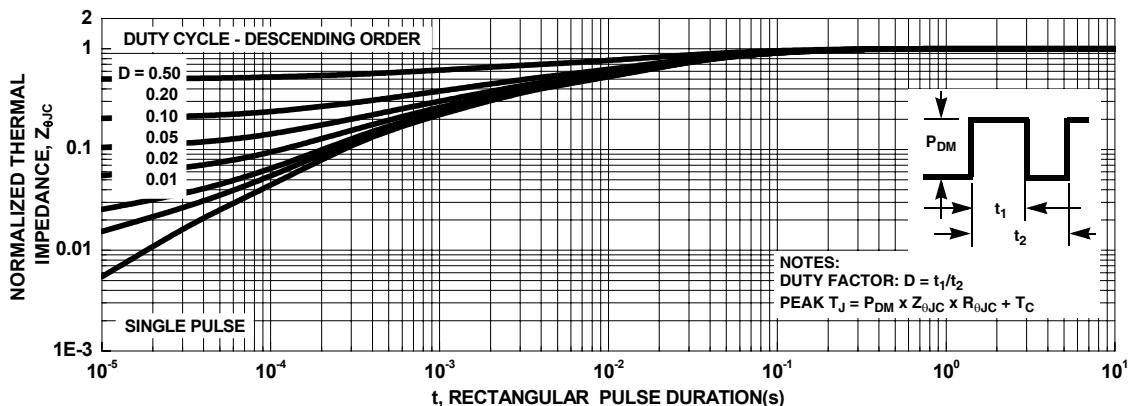


Figure 3. Normalized Maximum Transient Thermal Impedance

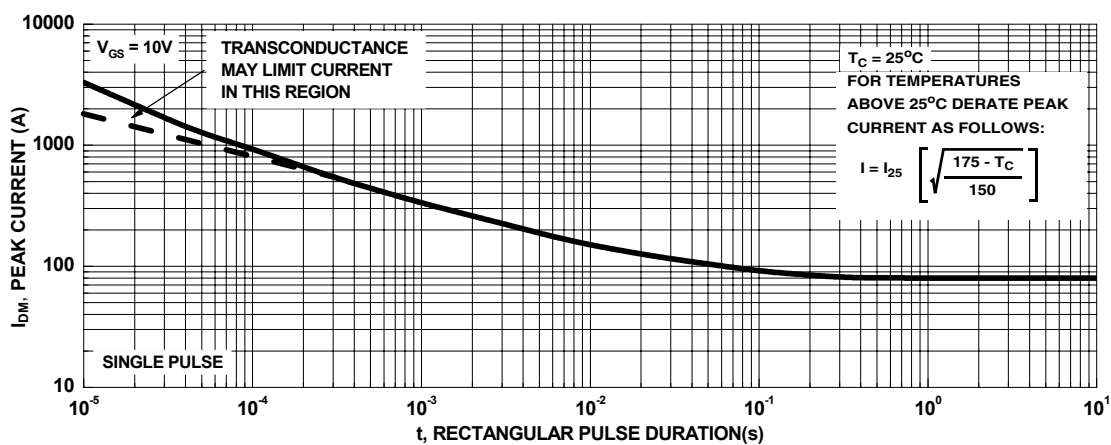


Figure 4. Peak Current Capability

Typical Characteristics

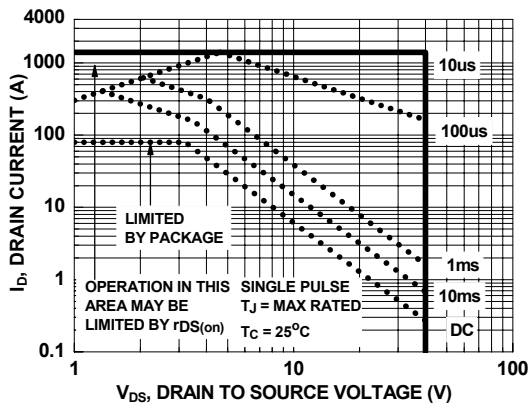


Figure 5. Forward Bias Safe Operating Area

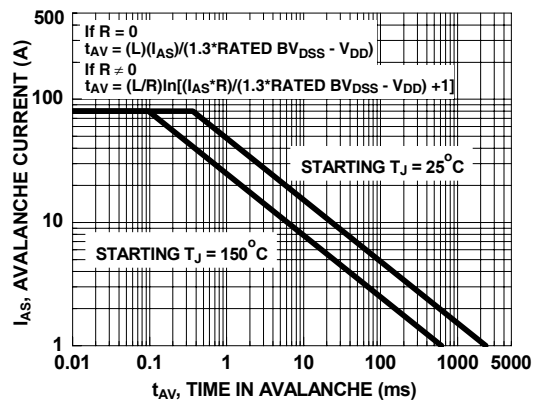


Figure 6. Unclamped Inductive Switching Capability

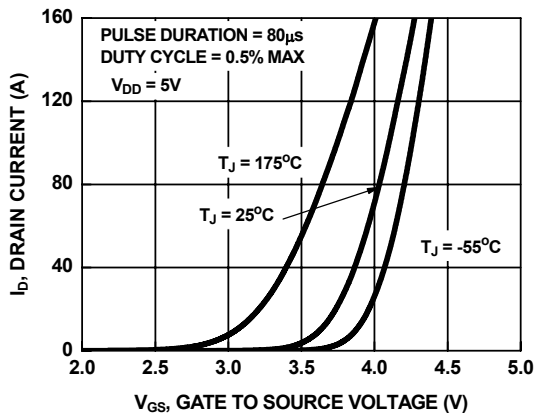


Figure 7. Transfer Characteristics

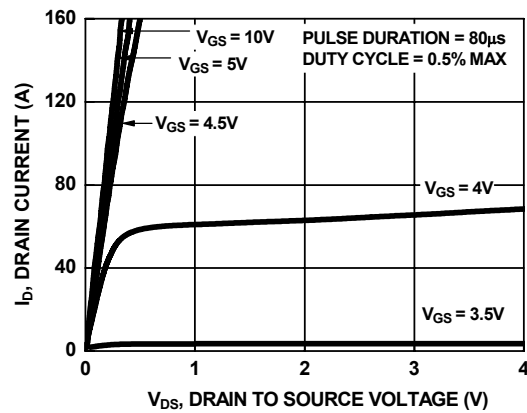


Figure 8. Saturation Characteristics

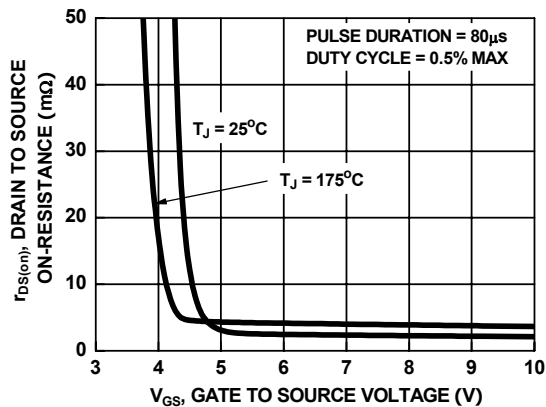


Figure 9. Drain to Source On-Resistance Variation vs Gate to Source Voltage

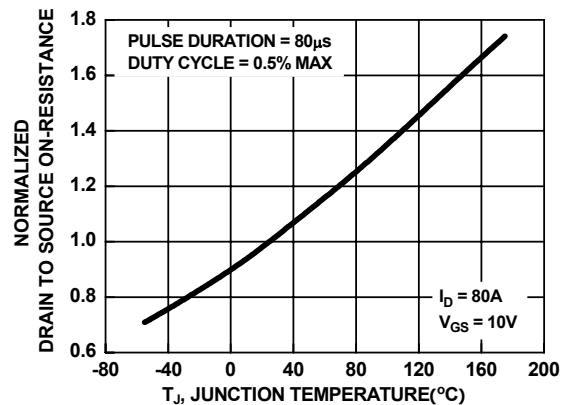


Figure 10. Normalized Drain to Source On-Resistance vs Junction Temperature

Typical Characteristics

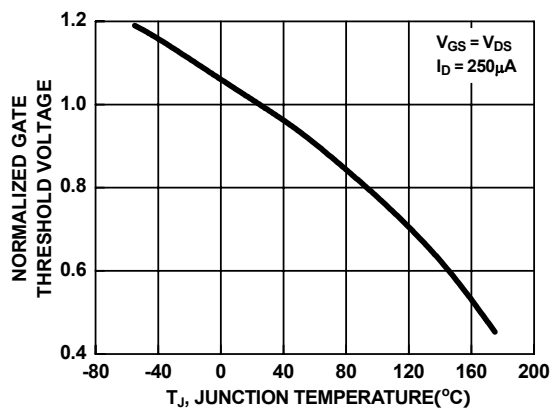


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

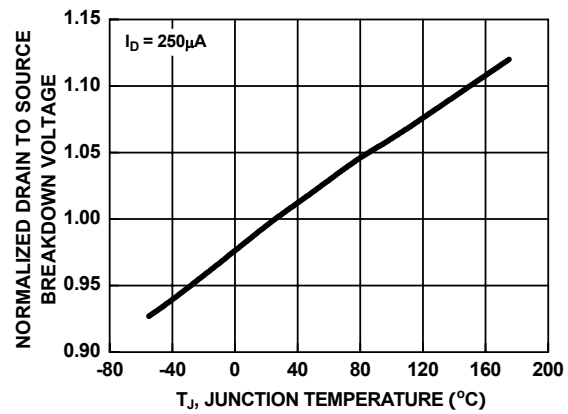


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

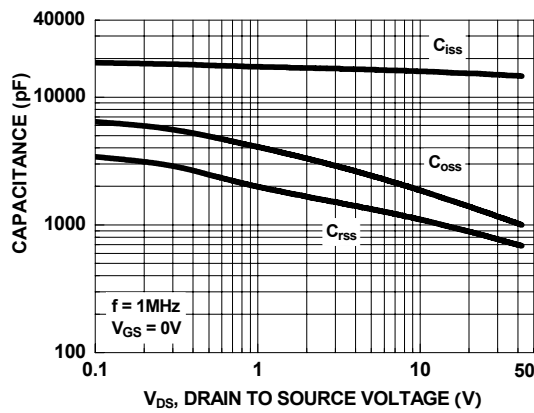


Figure 13. Capacitance vs Drain to Source Voltage

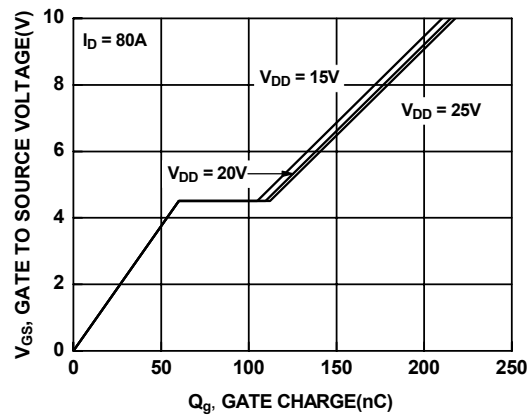


Figure 14. Gate Charge vs Gate to Source Voltage

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